

PROBE POLISH® PRODUCT DESCRIPTION



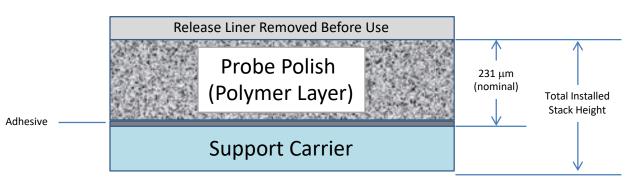
GENERAL

Probe Polish[®] is designed to remove embedded and bonded debris from probe shaped tips and collect any loose debris that was generated during probing. The abrasive material in the polymer will remove the accumulation of embedded or bonded debris but is not so aggressive that it will alter the probe material or probe contact area.

Frequent use of the Probe Polish[®], will reduce the number of touchdowns required to remove the embedded or bonded debris Probe card cleaning frequency and number of cleaning insertions varies according to the specific testing environment.

The cleaning motion with Probe Polish[®] is only in the Z direction. No lateral forces are applied to the probes. The forces exerted on the probe when cleaning with Probe Polish[®] are less than the forces as during normal testing operations.

The Probe Polish[®] polymer layer collects and traps the debris generated during cleaning. Reuse of the cleaning pad will cause the trapped debris to be pushed deeper into the polymer. This allows reuse of the same location several times. Visually check the pad from time to time to ensure that it does not become over-loaded with debris, which will reduce the cleaning efficiency of the material. To achieve maximum cleaning efficiency, offset each touchdown location approximately 2X the probe diameter in the XY directions, such that probe tip always touches the clean surface of the cleaning material.



CROSS SECTION

	Cleaning Material Configuration			
	Sheet	200mm Wafer	300mm Wafer	Custom Install
Polymer Layer Thickness	231 μm (nominal)	231 μm (nominal)	231 μm (nominal)	231 μm (nominal)
Support Carrier	143 μm (PET nominal)	725 ± 20μm (SEMI Standard)	775 ± 20μm (SEMI Standard)	Contact ITS
Total Installed Stack Height	374 ± 20μm	956 ± 30μm	1006 ± 30 μm	Contact ITS

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ROBE POLISH®

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For more information, please contact:

International Test Solutions | 1595 Meadow Wood Lane | Reno, NV 89502 (USA) <u>www.inttest.net</u> | mail: <u>sales@inttest.net</u> | Phone: +1 775-284-9220